

FMCAD 2022

# Error Correction Code Algorithm and Implementation Verification Using Symbolic Representations

Aarti Gupta, Roope Kaivola, Mihir Parang Mehta, Vaibhav Singh



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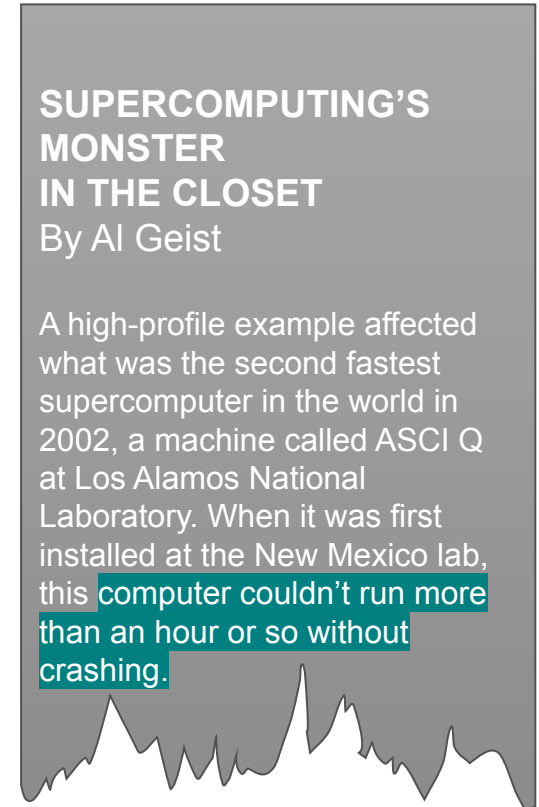
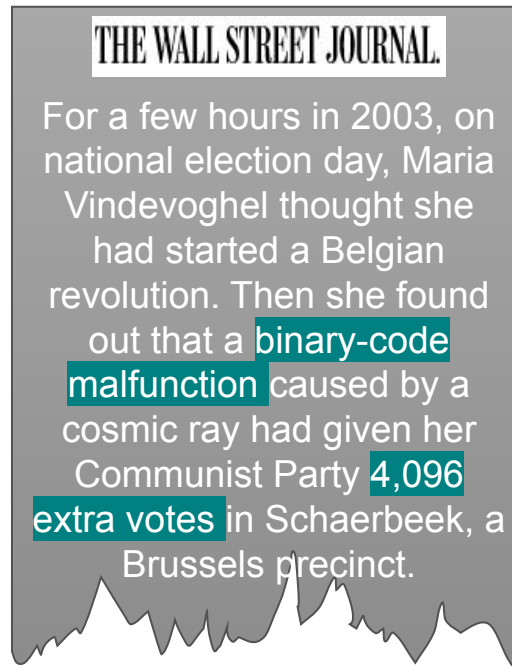
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# Background

- Data corruption due to **Soft Errors** (random, non-recurring bit errors in memory devices) can lead to system failures.
- **Error Correction Codes (ECCs)** were introduced in memory circuits to make systems fault-tolerant.
- ECCs cannot be verified fully using Traditional Dynamic Simulation, and **Formal Methods** are needed.



# Error Correction Codes

In a Nutshell

# Error Correction Codes

An error correction code (ECC) is an encoding scheme that transmits messages as binary numbers, in such a way that the message can be recovered even if some bits are erroneously flipped.

Parity Schemes

Hamming Codes

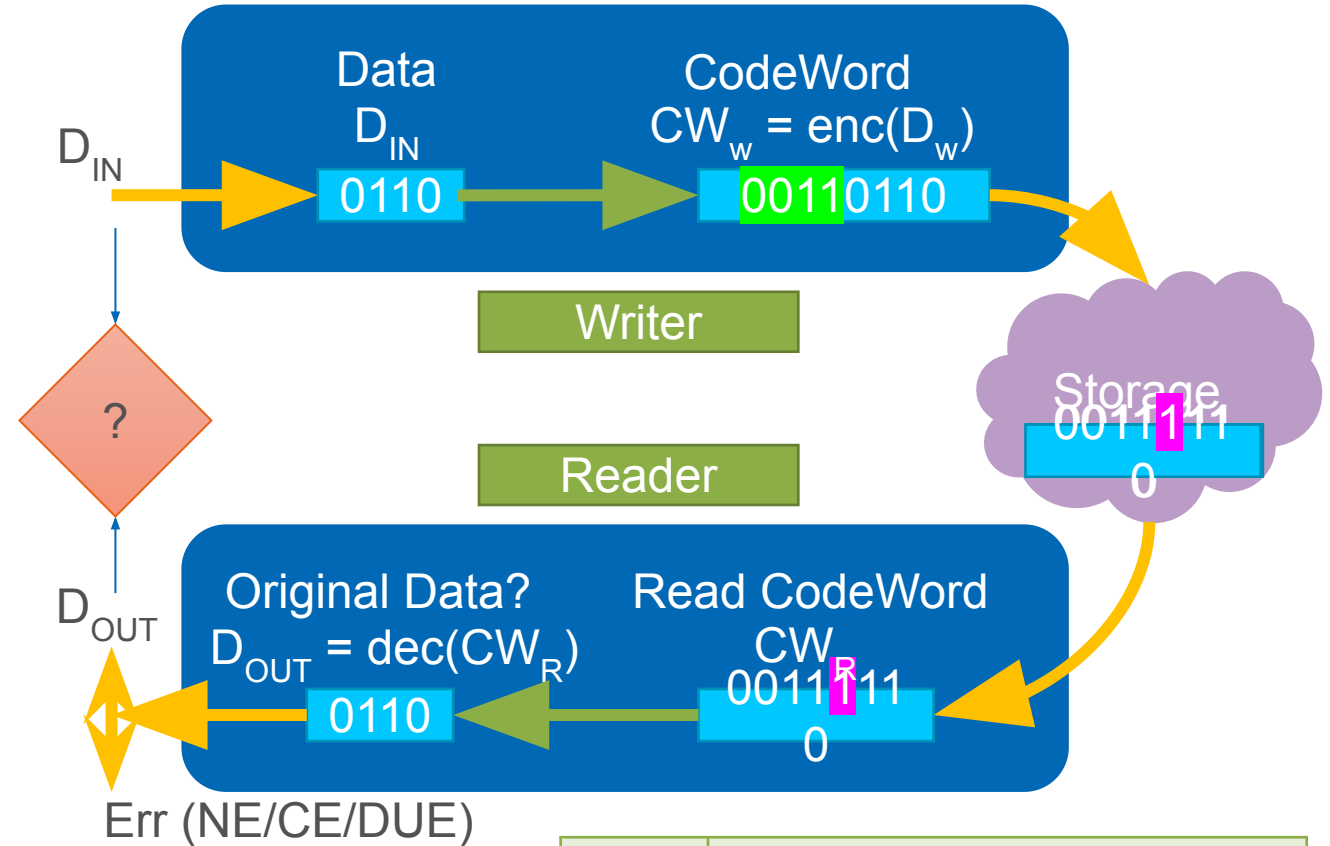
BCH Codes

Golay Codes

Reed-Solomon Codes

Customized Algorithms

Examples of ECC Algorithms

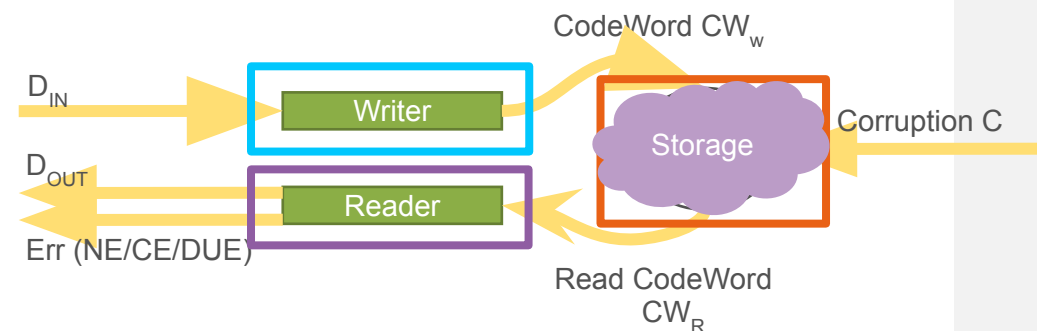


NE	No Error
CE	Correctable Error
DUE	Detectable but Uncorrectable Error

# Error Correction Codes

## Verification Challenges

# ECC: Simple Example



Writer/Encoder

$$\overrightarrow{CW_w} = \overrightarrow{D} \times G = (D[0] \ D[1] \ D[2] \ D[3]) \times \begin{pmatrix} 1 & 0 & 0 & 0 & 0 & 1 & 1 & 1 \\ 0 & 1 & 0 & 0 & 1 & 0 & 1 & 1 \\ 0 & 0 & 1 & 0 & 1 & 1 & 0 & 1 \\ 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 \end{pmatrix}$$

Summing operation in this matrix multiplication is modulo-2 which is equivalent to digital XOR operation

Storage/Corruption

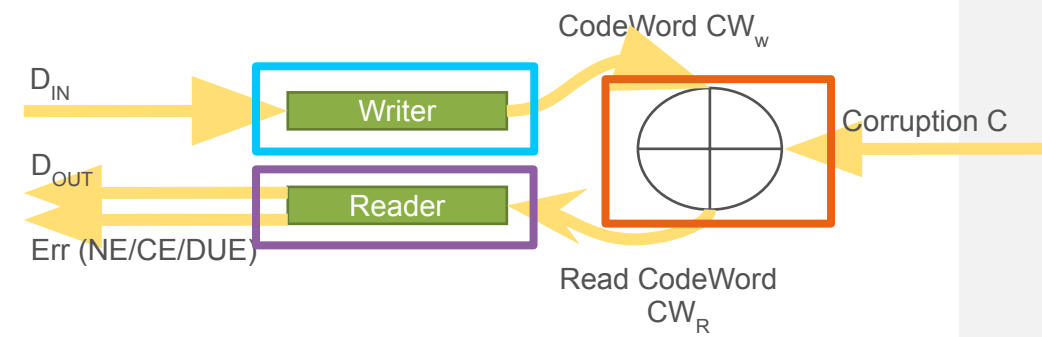
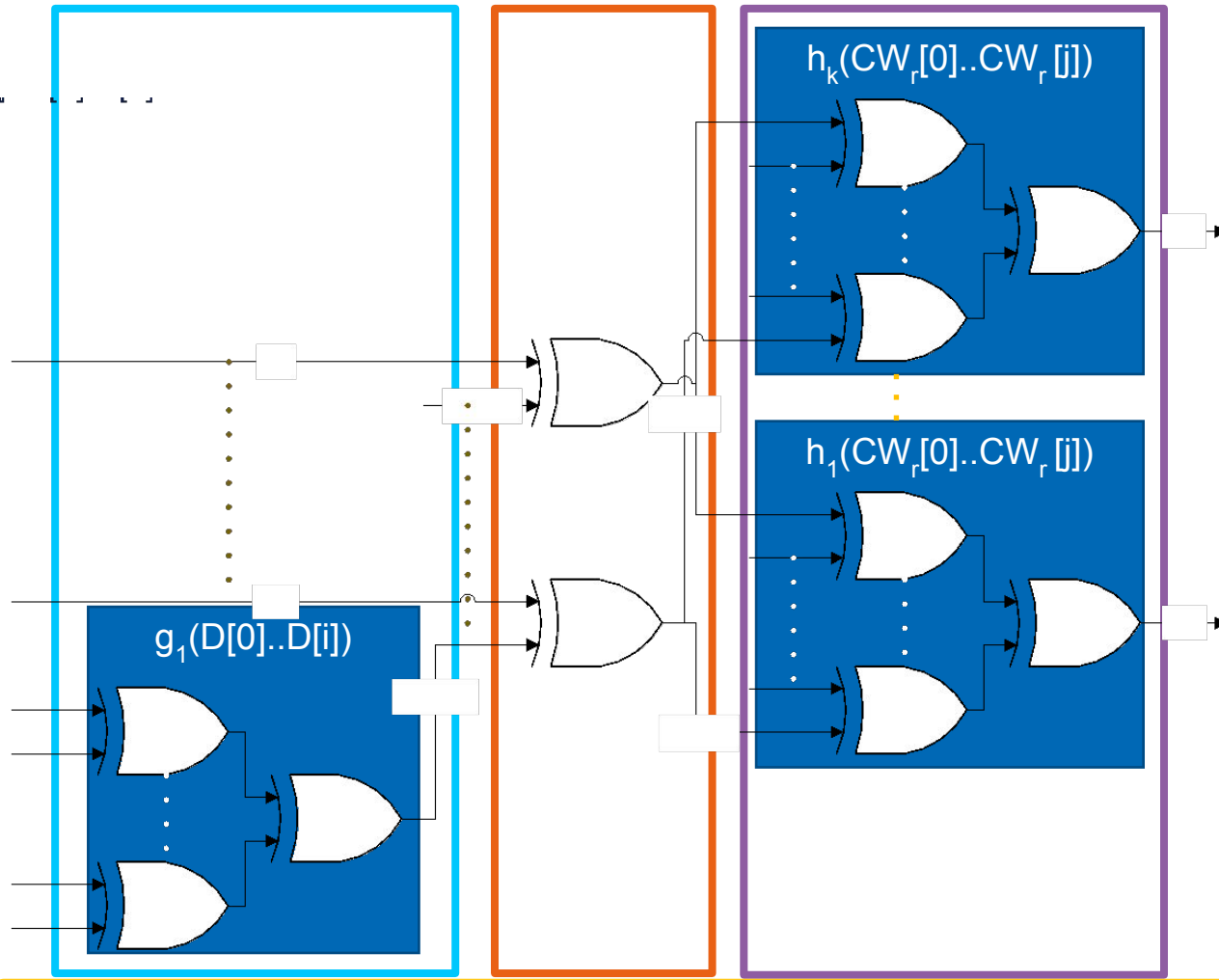
$$\overrightarrow{CW_r} = \overrightarrow{CW_w} \oplus \vec{C}$$

Reader/Decoder

$$\vec{S} = H \times \overrightarrow{CW_r}^T = \begin{pmatrix} 0 & 1 & 1 & 1 & 1 & 0 & 0 & 0 \\ 1 & 0 & 1 & 1 & 0 & 1 & 0 & 0 \\ 1 & 1 & 0 & 1 & 0 & 0 & 1 & 0 \\ 1 & 1 & 1 & 0 & 0 & 0 & 0 & 1 \end{pmatrix} \times \begin{pmatrix} D[0] \oplus C[0] \\ D[1] \oplus C[1] \\ D[2] \oplus C[2] \\ D[3] \oplus C[3] \\ D[1] \oplus D[2] \oplus D[3] \oplus C[4] \\ D[0] \oplus D[2] \oplus D[3] \oplus C[5] \\ D[0] \oplus D[1] \oplus D[3] \oplus C[6] \\ D[0] \oplus D[1] \oplus D[2] \oplus C[7] \end{pmatrix}$$

Syndrome S is decoded for error presence and location

# ECC: Implementation View



- Sea of XORs
- Dependent on each bit of data & corruption
- Model-checkers struggle on large designs
- Word-level engines don't help
- G & H matrices optimized frequently -> equivalence checking against a reference model impractical

**Bit-level nature of ECCs makes it an ideal candidate for Symbolic Simulation [Seeger, Bryant '95]**

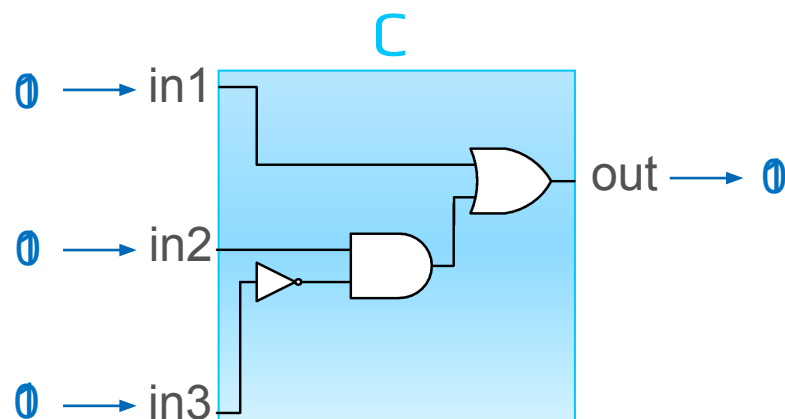


# Symbolic Simulation

## A Quick Overview

# Traditional Dynamic Simulation

**Problem: Verify that circuit C satisfies specification S.**

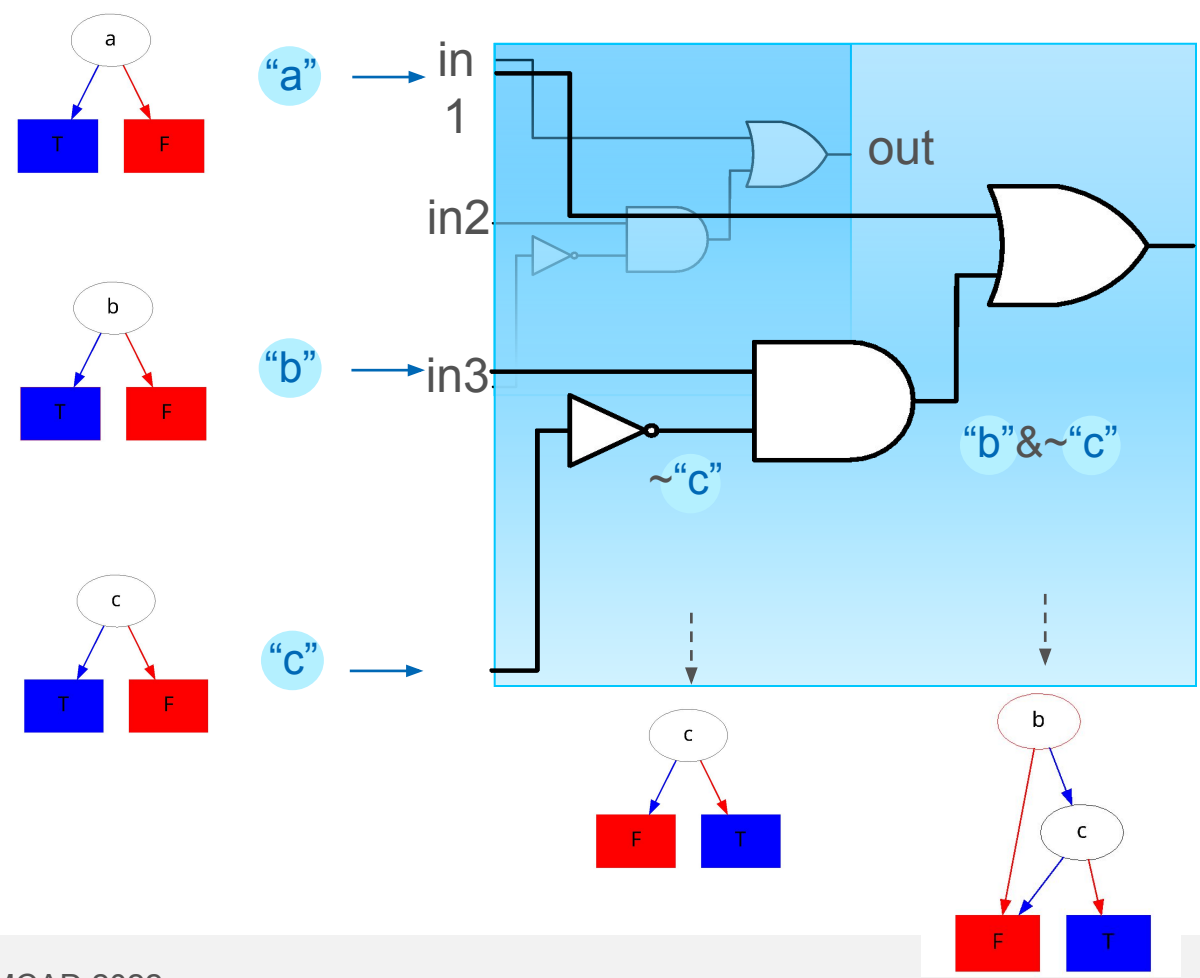


S

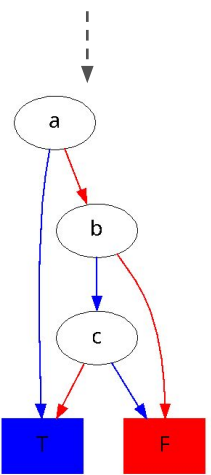
$$S(a,b,c) = a \text{ OR } (b \text{ AND NOT } c)$$

- Traditional simulation:
  - Inject random values and compare result to reference model
  - $2^n$  simulations to cover an n-bit wide logic.

# Symbolic Simulation



→ "a" | ("b" & ~"c")



S

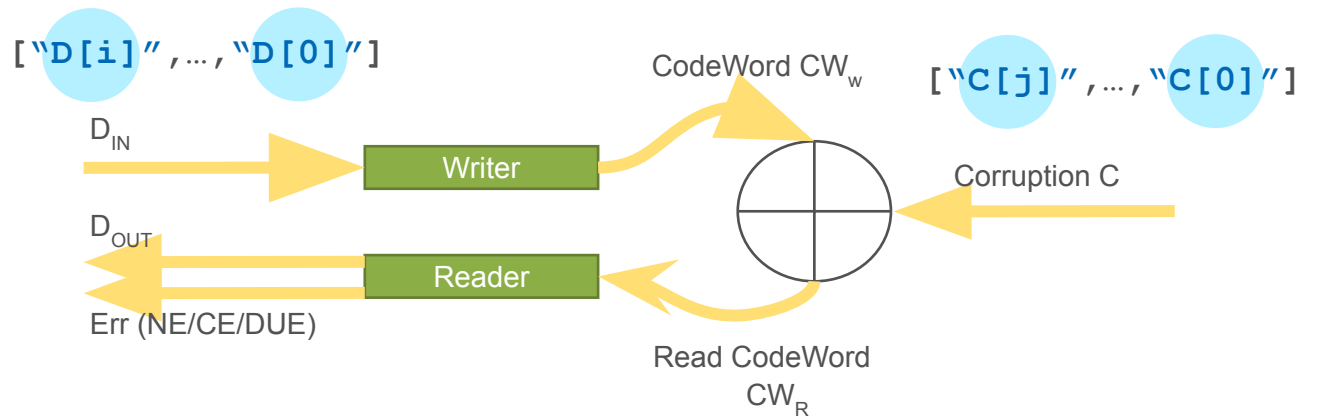
$S(a,b,c) = a \text{ OR } (b \text{ AND NOT } c)$

# ECC Verification

## Using Symbolic Simulation

# ECC Symbolic Analysis

Input and Output  
BDDs analyzed to  
guarantee correctness  
of ECC algorithm



Generic properties  
 $n$  Correction  
 $n+1$  Detection

- $(\text{Countbits}(C) = 0) \Rightarrow \text{NE and } D_{OUT} = D_{IN}$
- $0 < \text{Countbits}(C) \leq n \Rightarrow \text{CE and } D_{OUT} = D_{IN}$
- $(\text{Countbits}(C) = n + 1) \Rightarrow \text{DUE}$

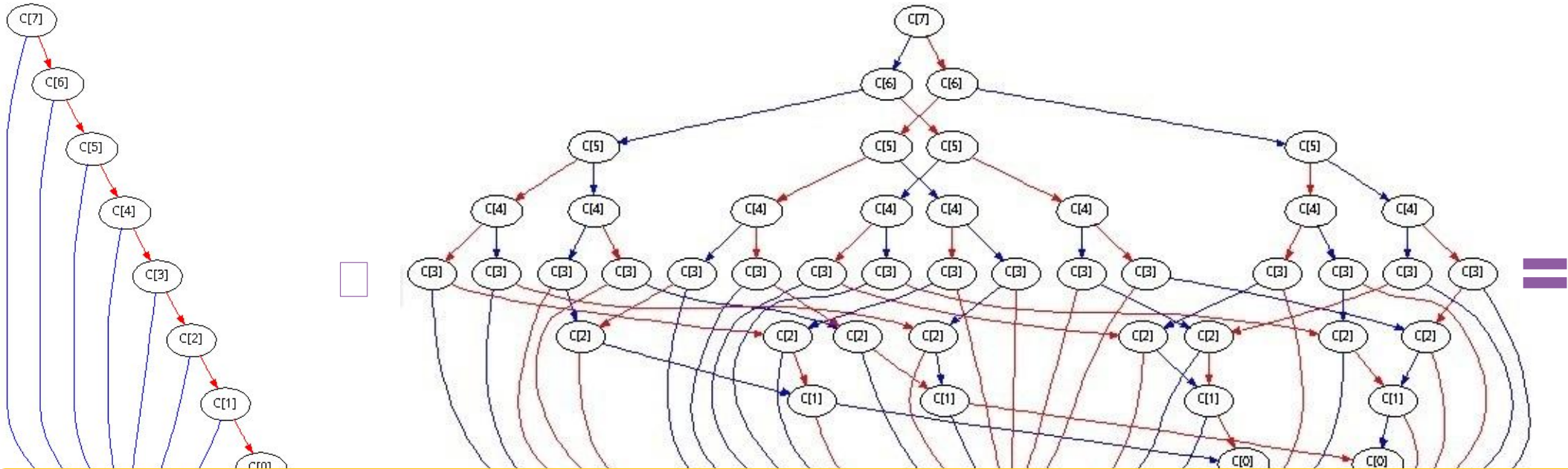
# ECC Symbolic Analysis

$(\text{Countbits}(C) = 0) \Rightarrow \text{NE}$

cond

check

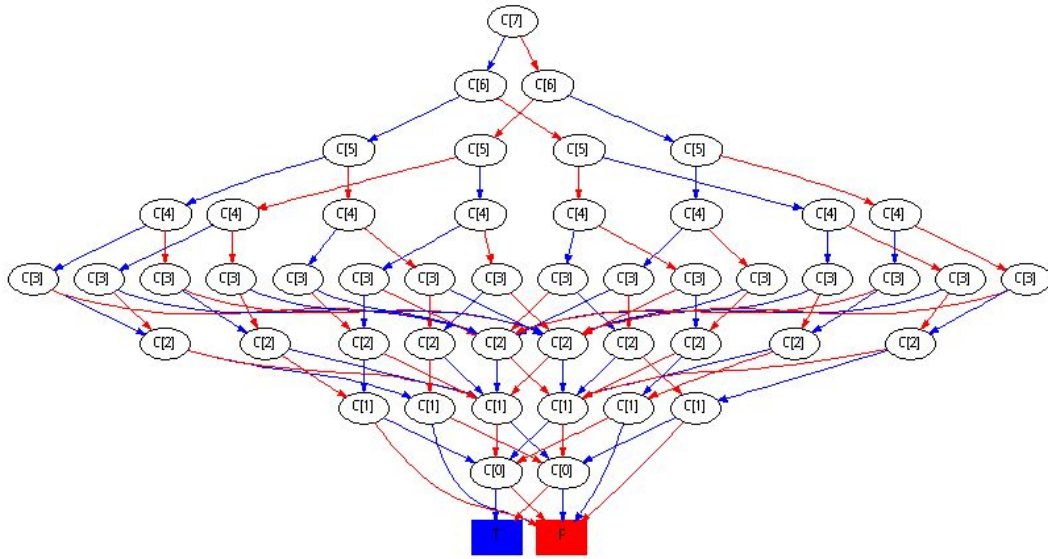
- $(\text{Countbits}(C) = 0) \Rightarrow \text{NE}$  and  $D_{\text{OUT}} = D_{\text{IN}}$
- $0 < \text{Countbits}(C) \leq n \Rightarrow \text{CE}$  and  $D_{\text{OUT}} = D_{\text{IN}}$
- $(\text{Countbits}(C) = n + 1) \Rightarrow \text{DUE}$



**End-to-End ECC functionality proven - No reference model needed!**

# Counting & Enumerating Satisfying Paths

## Example BDD for DUE (Uncorrectable Error)



Total Corruption Cases = 256

$\text{satCount}(\text{DUE}) = 112$

$\text{satCount}((\text{Countbits}(C) = 2) \text{ AND DUE}) = 28$

- Access to BDDs at all circuit nodes
- Allows symbolic reasoning on BDDs
- Satisfying assignments can be counted/enumerated under various conditions
- Helps in verifying fuzzy claims like:
  - “detects ~99.999% of error patterns”

# Results & Conclusion



# Results

Algorithm	Data Size (in bits)	Gate Count Range	Property Convergence		
			Symbolic Simulation	EDA Tool #1	EDA Tool #2
SECDED	Up to 512	7K-270K	Yes	Yes	Yes
SECDED	4096	~1M	Yes	No	No
DECTED	256, 512	150K-500K	Yes	No	No
TECQED	512	200K-700K	Yes	No	No
Custom Reed-Solomon Algorithms	Device (32b/64b) or Column(16b) Level protection	~1M	Yes	No	No

~30 different ECC designs verified in 2 years with **same** approach, without reference models

BDD Management Techniques Used in Symbolic Simulation Proofs:  
Symbolic Indexing, Parametric Substitution, Dynamic Weakening, Timed Causal Fanin Analysis, Case Splitting

Electronic Design Automation Tool #1: Model Checker; Tool #2: Commercial Datapath FV Tool

# Conclusion

- ECC algorithms fit nicely in the niche of symbolic simulation.
- BDD-based symbolic simulation approach scales up to industrial ECC designs
- Provides a closed-box approach, removing dependency from a reference model
- Verification can be moved to architectural stage by replacing Writer and Reader circuits with their High-Level Models
- Enables early optimizations of algorithms by means of symbolic counting

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